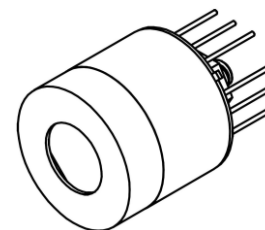


PVIA-4TE-13-1x1-TO8-wZnSeAR-36

**PRELIMINARY
DATASHEET**

**InAsSb superlattice
four-stage thermoelectrically-cooled
optically immersed
photovoltaic infrared detector**



FEATURES

- Spectral range: 2.0 to 13.6 μm
- RoHS-compliant III-V material
- Unique optical immersion technology applied
- Back-side illuminated
- Long term stability
- Fast response
- No minimum order quantity required

APPLICATIONS

- FTIR spectroscopy
- Gas detection, monitoring and analysis: C_2H_6
- Toxic gas detection
- Gas leak detection

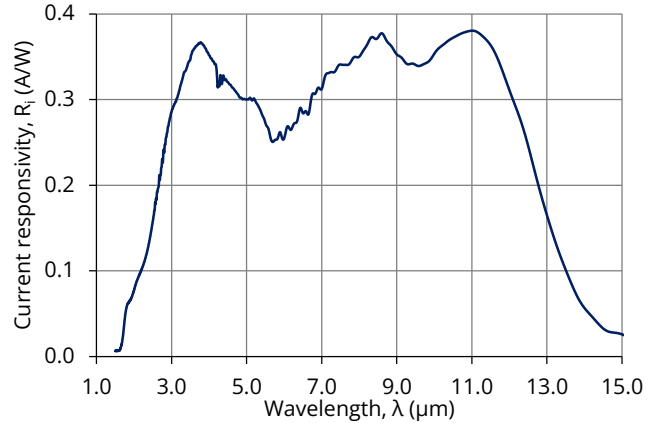
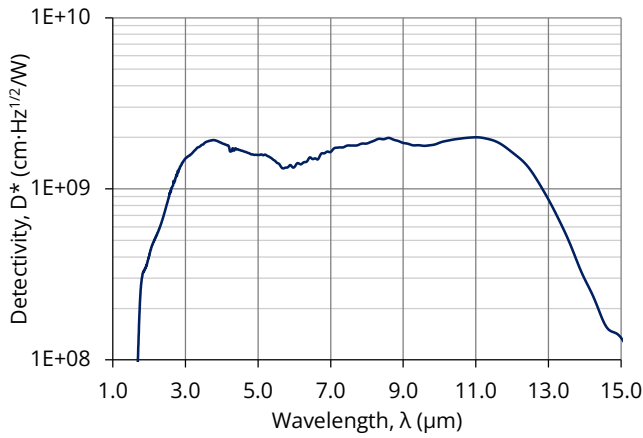
DETECTOR CONFIGURATION

Detector symbol	Cooling	Temperature sensor	Optical area, A_o , mm \times mm	Optical immersion	Package	Acceptance angle, Φ , deg.	Window
PVIA-4TE-13-1x1-TO8-wZnSeAR-36	4TE ($T_{\text{chip}} \cong 200\text{K}$)	thermistor	1 \times 1	hyperhemisphere	4TE-TO8	~ 36	wZnSeAR (3 deg. wedged zinc selenide, anti-reflection coating)

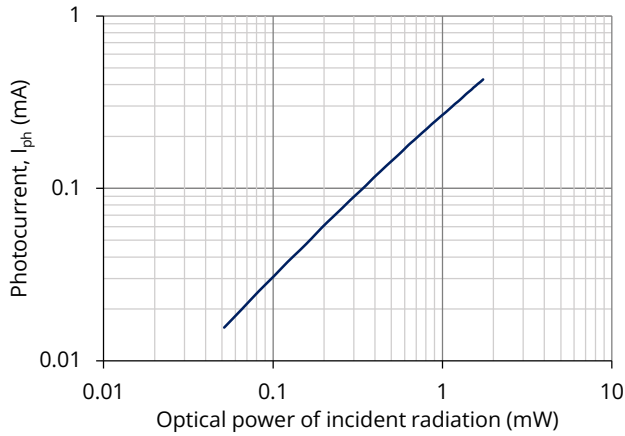
SPECIFICATION ($T_{\text{amb}} = 293\text{ K}$, $T_{\text{chip}} = 200\text{ K}$, $V_b = 0\text{ V}$)

Detector symbol	Cut-on wavelength (10%)		Peak wavelength	Cut-off wavelength (10%)		Detectivity		Current responsivity		Time constant	Dynamic resistance	
	$\lambda_{\text{cut-on}}$	λ_{peak}	$\lambda_{\text{cut-off}}$	$D^*(\lambda_{\text{peak}}, 20\text{kHz})$		$R_i(\lambda_{\text{peak}})$		τ	R_d			
	μm	μm	μm	$\text{cm}\cdot\text{Hz}^{1/2}/\text{W}$		A/W		ns	Ω			
	Max.	Typ.	Min.	Min.	Typ.	Min.	Typ.	Typ.	Min.	Typ.		
PVIA-4TE-13-1x1-TO8-wZnSeAR-36	2.0	10.5	13.6	2.0×10^9	3.0×10^9	0.25	0.38	3	90	120		

SPECTRAL RESPONSE (Typ., $T_{amb} = 293\text{ K}$, $T_{chip} = 200\text{ K}$)



LINEARITY (Typ., $T_{amb} = 293\text{ K}$, $\lambda = 4.55\ \mu\text{m}$)



MECHANICAL LAYOUT AND PINOUT

- [4TE-TO8\(12p\)-wW, PVI/PCI detector technical drawing](#)

RECOMMENDED AMPLIFIERS

Detector symbol	Preamplifier type
PVIA-4TE-13-1x1-TO8-wZnSeAR-36	AIP series
	PIP series
	MIP series
	SIP-TO8 series

ABSOLUTE MAXIMUM RATINGS

Parameter	Test conditions, remarks	Value	Unit
Ambient operating temperature, T_{amb}	Operation at $T_{amb} > 30^\circ\text{C}$ may increase the active element temperature and reduce the performance of the detector below specified parameters	-40 to 70	$^\circ\text{C}$
Storage temperature, T_{stg}		-40 to 85	$^\circ\text{C}$
Soldering temperature	Within 5 s or less	≤ 370	$^\circ\text{C}$
Storage humidity	No dew condensation	10 to 90	%
Maximum incident optical power density	Continuous wave (CW) or single pulses $> 1\ \mu\text{s}$ duration	2.5	W/cm^2
	Single pulses $< 1\ \mu\text{s}$ duration	10	kW/cm^2
Maximum bias voltage, $V_{b,max}$		-1.5	V
Maximum TEC voltage, $V_{TEC,max}$	4TE	8.3	V
Maximum TEC current, $I_{TEC,max}$	4TE	0.4	A

Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. Constant or repeated exposure to absolute maximum rating conditions may affect the quality and reliability of the device.